


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598934	<b>Applicant(s)/Patent Under Reexamination</b>  NAKAHATA ET AL.
	<b>Examiner</b>  SELIM AHMED	<b>Art Unit</b>  2826

SEARCHED			
Class	Subclass	Date	Examiner
257	13, 103	12/13/08	/sa/
438	46, 483, 481	12/13/08	/sa/

SEARCH NOTES		
Search Notes	Date	Examiner
Text search such as, Group III, III-V, nitride, GaN, GaInN, GaAlN, InGaN, AlGaIn, separate/sever/cleave/lasing/etching, substrate, crystal, nuclei/nucleus, seed, orientation, face, orientation, angle, degree, and their boolean combinations were searched.	12/13/08	/sa/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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